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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Complete if Known

Application Number	10/543,151
Confirmation Number	2634
Application Filing Date	April 18, 2006
First Named Inventor	Kenji WATANABE
Art Unit	2881
Examiner Name	Kiet Tuan Nguyen
Attorney Docket Number	052886

Sheet 1 of 1

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US			
		US			
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁴
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
	1	WO	99/46798	A1	09-16-1999	Hitachi Ltd.	Abstract
	2	EP	0 949 653	A2	10-13-1999	Hitachi, Ltd.; Hitachi Instruments Engineering Co., Ltd.; Hitachi Science Systems, Ltd.	N/A
	3	JP	2002 141013	A	05-17-2002	Hitachi Ltd.	Abstract Only
	4	WO	00/72355	A1	11-30-2000	Klatencor Corporation	N/A

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁴
	5	ANONYMOUS; "Electron Energy Discriminator for Wafer/Chip Testing", <i>IBM Technical Disclosure Bulletin</i> , Vol. 23, No. 6, November 1980, pages 2288-2290	N/A
	6	ZHU W ET AL.; "Large current density from carbon nanotube field emitters"; <i>Applied Physics Letters</i> , American Institute of Physics, New York, US; Vol. 75, No. 6; August 9, 1999; pages 873-875	N/A
	7	International Search Report mailed August 6, 2004 in Corresponding International Application No. PCT/JP2004/000711	N/A

Examiner Signature	/Kiet Tuan Nguyen/	Date Considered	05/04/2009
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to indicate here if English language Translation is attached.